

Notice of References Cited	Application/Control No. 10/767,038	Applicant(s)/Patent Under Reexamination CLARKE ET AL.	
	Examiner Elias Desta	Art Unit 2857	Page 1 of 1

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	B	US-4,625,332	11-1986	Singer et al.	455/67.14
	C	US-6,707,979	03-2004	Wang et al.	385/140
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.